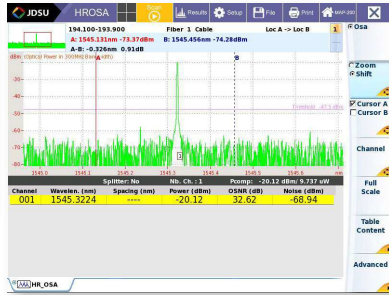


mHROSA-A1

MAP-200 Integrated Multi-Wavelength Wavemeter and High-Resolution Optical Spectrum Analyzer (OSA)



Key Benefits

- Industry’s first integrated multi-wavelength meter and high-resolution OSA for lab and production
- Enables sub-GHz resolution analysis of optical signals
- Supports 400 G Nyquist flexible grid WDM signal analysis
- MAP-based modular design enables process integration into more comprehensive optical devices
- A complement to the comprehensive MAP solution portfolio
- No moving parts

Key Features

- Sub-GHz wavelength resolution
- Extended C-band acquisition range
- Measures frequency, power level, and OSNR
- Continuous and averaging test modes
- Measures Side-mode suppression ratio

Applications

- DWDM transmission systems
- Optical sources
- Transponders and linecards
- Qualify 10/40/100/400 G components and systems
- Validate and deploy 100 G and 400 G flex-grid DWDM

JDSU brings next-generation innovation in wavelength testing to optical lab and manufacturing environments. The new MAP-based integrated multi-wavelength meter and high resolution OSA module combines sub-GHz resolution performance and compact modularity in a single-slot cassette. It works in MAP-230B and MAP-280 mainframes and it can take advantage of the wide array of other JDSU MAP modules such as power meters, attenuators, switches, sources, and a range of signal conditioning modules. It is a richly featured multi-wavelength meter and high-resolution OSA with analysis features that can be controlled through an easy-to-use GUI or the MAP-200 automation interface.

Based on coherent detection techniques, it has no moving parts and it provides unprecedented frequency resolution to precisely report the power level and central frequencies of densely spaced optical signals as close as 2 GHz.

This ground-breaking solution provides the ideal solution for both lab and manufacturing test systems where reliability, compactness, and performance are critical.

Platform Compatibility

MAP-230B

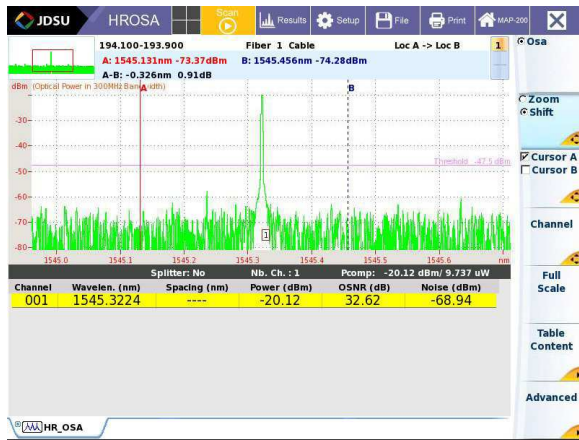


3-slot mainframe

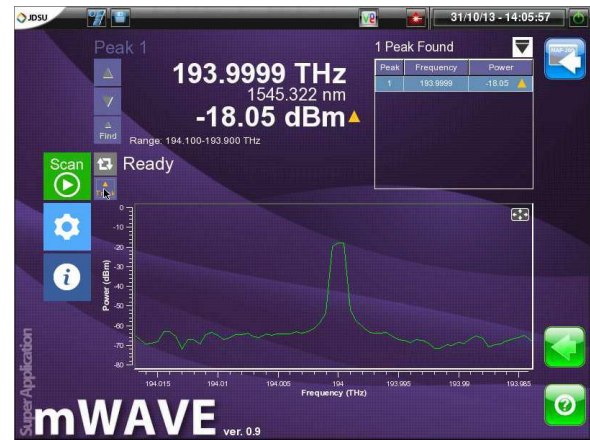
MAP-280/MAP-280R



8-slot mainframe



HROSA GUI with graphing capability and analysis tools



Wavemeter GUI with tabulated wavelengths, powers, and low-resolution graph

Specifications (at 25°C ±5° over the entire frequency range)

Spectral

Optical frequency (wavelength) range	191.1 – 196.4 THz (1526.44 – 1568.77 nm)
Absolute uncertainty of frequency (wavelength) ¹	±370 MHz (±3 pm)
Minimum resolvable separation	2 GHz (16 pm)
Resolution bandwidth	300 MHz
Resolution bandwidth settings	
Display resolution	0.0001 nm

Power

Input power range (per channel)	-60 to +10 dBm
Noise floor	-75 dBm
Max. safe total input power	+17 dBm
Absolute uncertainty of power level ^{1,4}	±0.5 dB
Power linearity ⁵	±0.4 dB
Polarization dependence	±0.2 dB
Display resolution	0.01 dB

Other

Return loss	>50 dB
Measurement time ⁶	<1.0 s
Fiber type	9/125 μm single-mode fiber
Connector type	FC/APC
Operating temperature	10 to 40°C
Storage temperature	-20 to +50°C
Humidity	Maximum 95% RH from 10 to 40 C non-condensing
Dimensions	4.06 x 13.26 x 37.03 cm
Weight	1.4 kg
Calibration period	1 year

- Over the entire frequency range.
- Power of unmodulated single-frequency laser or peak power of modulated signal in 300 MHz optical bandwidth.
- Total power for all input signals.
- At -20 dBm input power.
- For input power from -10 to -40 dBm.
- Over 50 GHz sweep range, no averaging.

Ordering Information

Description

MAP-200 extended C-band integrated multi-wavelength meter and high-resolution optical spectrum analyzer

Part Number

mHROSA-A1CB10

Network and Service Enablement Regional Sales

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